

FORM PTO-1449 (modified)
 To: U.S. Department of Commerce
 (PW FORM PAT-1449)
 Patent and Trademark Office

Atty. Dkt. No.	M#	Client Ref.
	307720	P-1503.020-US

Applicant: STEVEN HANSEN
Appln. No.: 10/773,397 10/773,397
Filing Date: February 9, 2004

Date: February 9, 2004

Page 1 of 1

Examiner: Unassigned Group Art Unit: Unassigned

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
AM	AR 5,305,054	04/1994	SUZUKI et al.			
	BR 5,523,193	06/1996	NELSON			
	CR 6,049,660	04/2000	AHN et al.			
	DR 6,452,662	09/2002	MULKENS et al.			
	ER 6,463,403 B1	10/2002	BURDORF et al.			
	FR 6,466,304	10/2002	SMITH			
	GR 2002/0035461 A1	03/2002	CHANG et al.			
V	HR 2002/0167653 A1	11/2002	MULKENS et al.			
	IR 2003/0093251 A1	05/2003	CHANG			
JR						
KR						
LR						
MR						
NR						
OR						
PR						

FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
					Enclosed	No	Enclose	No
QR								
RR								
SR								
TR								
UR								
VR								
WR								
XR								
YR								
ZR								

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

AAR		
BBR		
CCR		
DDR		

Examiner *Alan Mathews*

Date Considered: *8-7-2005*

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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Filing Date: February 9, 2004

Examiner: TBA Group Art Unit: 1558

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

AUG 27 2004

Date: August 27, 2004

1 of

1

U.S. PATENT DOCUMENTS

Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
A1	AR	2003/0073013 A1	04/2003	Hsu et al.			
	BR						
	CR						
	DR						
	ER						
	FR						
	GR						
	HR						
	IR						
	JR						
	KR						
	LR						

FOREIGN PATENT DOCUMENTS

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						Enclosed	No	Enclose	No

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

MR				
NR				
OR				
PR				
QR				
RR				
SR				
TR				
UR				
VR				
WR				
XR				

Examiner *Alan Mathews*

Date Considered: *8 - 5 - 2005*

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**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Date: May 10, 2004

Page **1** of **1**

Applicant: HANSEN

Appln. No.: 10/773,397

Filing Date: February 9, 2004

Examiner: NOT
ASSIGNED

Group Art Unit: NOT
ASSIGNED

U.S. PATENT DOCUMENTS

Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
AM	AR	5,680,588	10/1997	Gortych et al.			
	BR	2002/0045106 A1	04/2002	Baselmans et al.			
	CR	2002/0062206 A1	05/2002	Liebchen			
	DR	2002/0152452 A1	10/2002	Socha			
	ER	2003/0082463 A1	05/2003	Laidig et al.			

FOREIGN PATENT DOCUMENTS

		Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract	Translation Readily Available
						Enclosed	No

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

AM	FR	Burkhardt et al., "Illuminator Design for the Printing of Regular Contact Patterns," <i>Microelectronic Engineering</i> , Vol. 41, No. 42, 1998, pp. 91-96.			
	GR	Chen et al., "Practical Method for Full-Chip Optical Proximity Correction," <i>SPIE</i> , Vol. 3051, 1997, pp. 790-803.			
	HR	Chen et al., "Optical Proximity Correction for Intermediate-Pitch Features Using Sub-Resolution Scattering Bars," <i>Journal of Vacuum Science & Technology B</i> , Vol. 15, No. 6, Nov/Dec 1997, pp. 2426-2433.			
	IR	Flagello et al., "Lithographic Lens Testing: Analysis of Measured Aerial Images, Interferometric Data and Photoresist Measurements," <i>SPIE Microlithography Seminar</i> , 1996.			
	JR	Flagello et al., "Towards a Comprehensive Control of Full-Field Image Quality in Optical Photolithography," <i>SPIE Microlithography Seminar</i> , March 1997.			
	KR	Gau et al., "Strategy to Manipulate the Optical Proximity Effect by Post-Exposure Bake Processing," <i>SPIE</i> , Vol. 3334, 1998, pp. 885-891.			
	LR	Gau et al., "The Customized Illumination Aperture Filter for Low k ₁ Photolithography Process," <i>SPIE</i> , Vol. 4000, March 2000, pp. 271-282.			
	MR	Hsia et al., "Customized Off-Axis Illumination Aperture Filtering for Sub-0.18 μm KrF Lithography," <i>SPIE</i> , Vol. 3679, March 1999, pp. 427-434.			
	NR	Liu et al., "The Application of Alternating Phase-Shifting Masks to 140 nm Gate Patterning: Line Width Control Improvements and Design Optimization," <i>SPIE</i> , Vol. 3236, 1998, pp. 328-337.			
	OR	Smith et al., "Illumination Pupil Filtering Using Modified Quadrupole Apertures," <i>SPIE</i> , Vol. 3334, 1998, pp. 384-394.			
	PR	Suzuki et al., "Multilevel Imaging System Realizing k ₁ =0.3 Lithography," <i>SPIE</i> , Vol. 3679, March 1999, pp. 396-407.			
	QR	Wong et al., "Level-Specific Lithography Optimization for 1-Gb DRAM," <i>IEEE Transactions on Semiconductor Manufacturing</i> , Vol. 13, No. 1, February 2000, pp. 76-87.			

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HANSEN - 10/773,397
Docket No. 081468-0307720

APPENDIX

Examiner's Initials	First Inventor	Application No.	Filing Date	Enclosed
AM	Liebchen	10/705,234	November 12, 2003	<input checked="" type="checkbox"/> Specification <input checked="" type="checkbox"/> Drawings <input checked="" type="checkbox"/> Other: Claims

The Examiner's initials indicates he/she has considered the cited application relative to the subject application.

DO NOT PRINT the above information on the patent which results from the subject application.

alan Mathews

Date Considered

8-7-2005